

Search Notes



Application/Control No.

10/759,816

Examiner

Hae M. Hyeon

Applicant(s)/Patent under Reexamination

BOEMMEL ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	492	2/05	hnh
439	493		
439	495		
439	496		
439	499		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
439/67 & 77 cursory	2/05	hnh